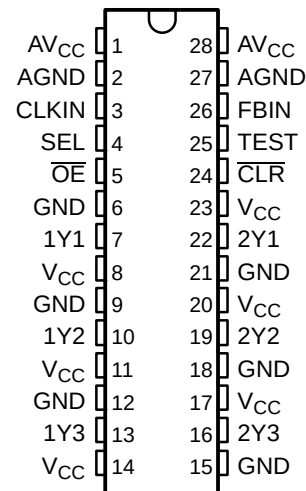


3.3-V PHASE-LOCK LOOP CLOCK DRIVER WITH 3-STATE OUTPUTS

FEATURES

- Low-Output Skew for Clock-Distribution and Clock-Generation Applications
- Operates at 3.3-V V_{CC}
- Distributes One Clock Input to Six Outputs
- One Select Input Configures Three Outputs to Operate at One-Half or Double the Input Frequency
- No External RC Network Required
- External Feedback Pin (FBIN) Is Used to Synchronize the Outputs to the Clock Input
- Application for Synchronous DRAM, High-Speed Microprocessor
- Negative-Edge-Triggered Clear for Half-Frequency Outputs
- TTL-Compatible Inputs and Outputs
- Outputs Drive 50- Ω Parallel-Terminated Transmission Lines
- State-of-the-Art *EPIC-IITM* BiCMOS Design Significantly Reduces Power Dissipation
- Distributed V_{CC} and Ground Pins Reduce Switching Noise
- Packaged in Plastic 28-Pin Shrink Small Outline Package

DB OR DL PACKAGE
(TOP VIEW)



DESCRIPTION

The CDC536 is a high-performance, low-skew, low-jitter clock driver. It uses a phase-lock loop (PLL) to precisely align, in both frequency and phase, the clock output signals to the clock input (CLKIN) signal. It is specifically designed for use with synchronous DRAMs and popular microprocessors operating at speeds from 50 MHz to 100 MHz or down to 25 MHz on outputs configured as half-frequency outputs. The CDC536 operates at 3.3-V V_{CC} and is designed to drive a 50- Ω transmission line.

The feedback input (FBIN) is used to synchronize the output clocks in frequency and phase to the input clock (CLKIN). One of the six output clocks must be fed back to FBIN for the PLL to maintain synchronization between CLKIN and the outputs. The output used as the feedback pin is synchronized to the same frequency as CLKIN.

The Y outputs can be configured to switch in phase and at the same frequency as CLKIN. The select (SEL) input configures three Y outputs to operate at one-half or double the CLKIN frequency depending on which pin is fed back to FBIN (see Tables 1 and 2). All output signal duty cycles are adjusted to 50% independent of the duty cycle at the input clock.

Output-enable ($\overline{OE}$) is provided for output control. When $\overline{OE}$ is high, the outputs are in the high-impedance state. When $\overline{OE}$ is low, the outputs are active. TEST is used for factory testing of the device and can be used to bypass the PLL. TEST should be strapped to GND for normal operation.



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EPIC-II is a trademark of Texas Instruments.

Unlike many products containing PLLs, the CDC536 does not require external RC networks. The loop filter for the PLL is included on-chip, minimizing component count, board space, and cost.

Because it is based on PLL circuitry, the CDC536 requires a stabilization time to achieve phase lock of the feedback signal to the reference signal. This stabilization time is required following power up and application of a fixed-frequency, fixed-phase signal at CLKIN as well as following any changes to the PLL reference or feedback signals. Such changes occur upon change of the select inputs, enabling the PLL via TEST, and upon enable of all outputs via $\overline{OE}$.

The CDC536 is characterized for operation from 0°C to 70°C.

DETAILED DESCRIPTION OF OUTPUT CONFIGURATIONS

The voltage-controlled oscillator (VCO) in the CDC536 has a frequency range of 100 MHz to 200 MHz, twice the operating frequency range of the CDC536 outputs. The output of the VCO is divided by two and by four to provide reference frequencies with a 50% duty cycle of one-half and one-fourth the VCO frequency. The SEL0 and SEL1 inputs determine which of the two signals are buffered to each bank of device outputs.

One device output must be externally wired to FBIN to complete the PLL. The VCO operates such that the frequency of this output matches that of the CLKIN signals. In the case that a VCO/2 output is wired to FBIN, the VCO must operate at twice the CLKIN frequency, resulting in device outputs that operate at the same or one-half the CLKIN frequency. If a VCO/4 output is wired to FBIN, the device outputs operate at the same or twice the CLKIN frequency.

Output Configuration A

Output configuration A is valid when any output configured as a 1× frequency output in Table 1 is fed back to the FBIN input. The input frequency range for the CLKIN input is 50 MHz to 100 MHz when using output configuration A. Outputs configured as 1/2× outputs operate at half the CLKIN frequency, while outputs configured as 1× outputs operate at the same frequency as the CLKIN input.

Table 1. Output Configuration A

INPUTS	OUTPUTS	
	1/2× FREQUENCY	1× FREQUENCY
L	None	All
H	1Yn	2Yn

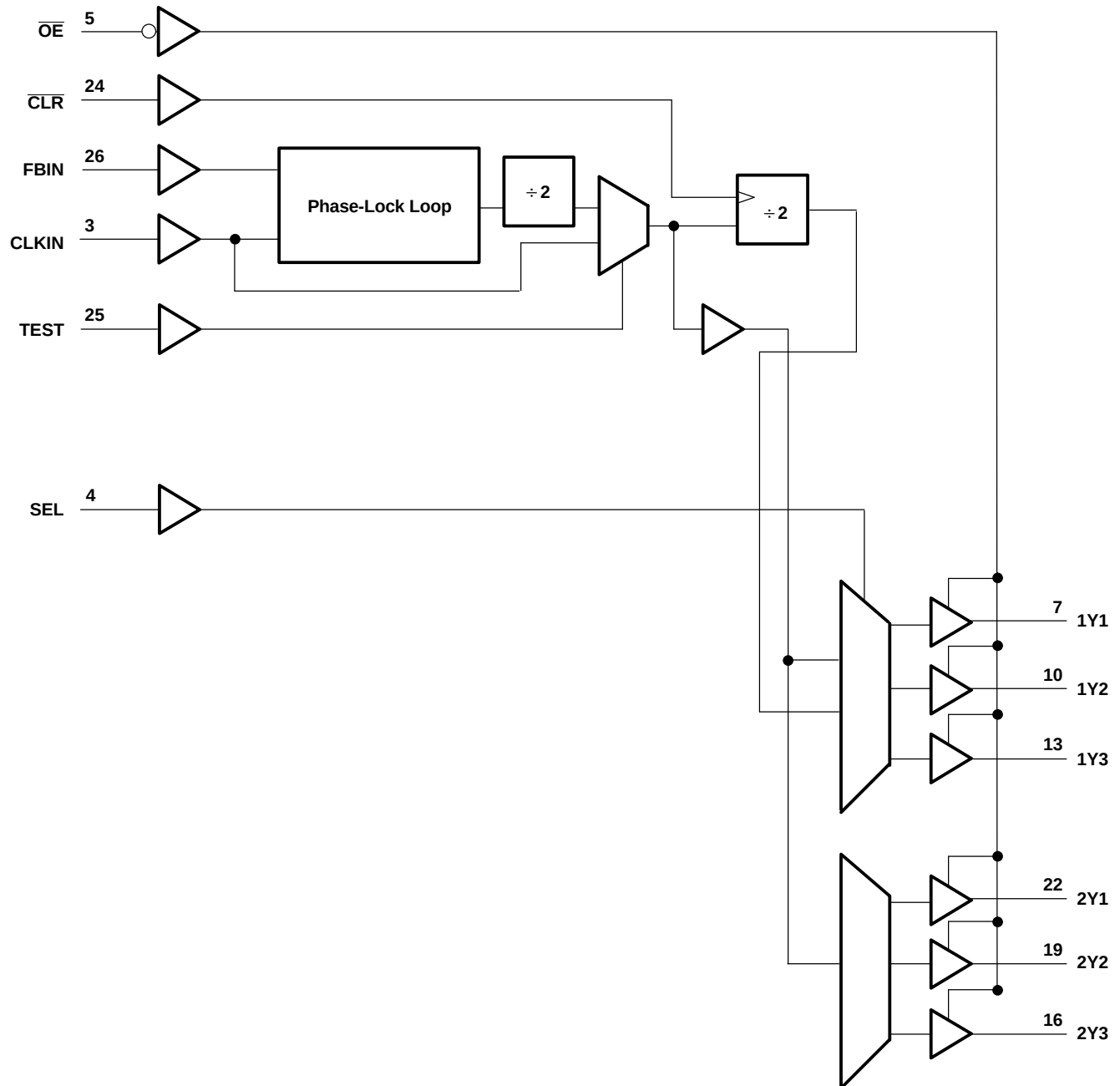
Output Configuration B

Output configuration B is valid when any output configured as a 1× frequency output in Table 2 is fed back to FBIN. The input frequency range for the CLKIN input is 25 MHz to 50 MHz when using output configuration B. Outputs configured as 1× outputs operate at the CLKIN frequency, while outputs configured as 2× outputs operate at double the frequency of the CLKIN input.

Table 2. Output Configuration B

INPUTS	OUTPUTS	
	1× FREQUENCY	2× FREQUENCY
L	All	None
H	1Yn	2Yn

FUNCTIONAL BLOCK DIAGRAM



FUNCTIONAL BLOCK DIAGRAM (continued)**Terminal Functions**

TERMINAL NAME	NO.	I/O	DESCRIPTION
CLKIN	3	I	Clock input. CLKIN provides the clock signal to be distributed by the CDC536 clock-driver circuit. CLKIN is used to provide the reference signal to the integrated phase-lock loop that generates the clock output signals. CLKIN must have a fixed frequency and fixed phase in order for the phase-lock loop to obtain phase lock. Once the circuit is powered up and a valid CLKIN signal is applied, a stabilization time is required for the phase-lock loop to phase lock the feedback signal to its reference signal.
$\overline{\text{CLR}}$	24	I	$\overline{\text{CLR}}$ is used for testing purposes only. Connect $\overline{\text{CLR}}$ to GND for normal operation.
FBIN	26	I	Feedback input. FBIN provides the feedback signal to the internal PLL. FBIN must be hardwired to one of the six clock outputs to provide frequency and phase lock. The internal PLL adjusts the output clocks to obtain zero phase delay between the FBIN and differential CLKIN inputs.
$\overline{\text{OE}}$	5	I	Output enable. $\overline{\text{OE}}$ is the output enable for all outputs. When $\overline{\text{OE}}$ is low, all outputs are enabled. When $\overline{\text{OE}}$ is high, all outputs are in the high-impedance state. Since the feedback signal for the phase-lock loop is taken directly from an output, placing the outputs in the high-impedance state interrupts the feedback loop; therefore, when a high-to-low transition occurs at $\overline{\text{OE}}$, enabling the output buffers, a stabilization time is required before the phase-lock loop obtains phase lock.
SEL	4	I	Output configuration select. SEL selects the output configuration for each output bank (e.g. 1×, 1/2×, or 2×).(see Tables 1 and 2).
TEST	25	I	TEST is used to bypass the phase-lock loop circuitry for factory testing of the device. When TEST is low, all outputs operate using the PLL circuitry. When TEST is high, the outputs are placed in a test mode that bypasses the PLL circuitry. TEST should be grounded for normal operation.
1Y1-1Y3	7, 10, 13	O	These outputs are configured by SEL to transmit one-half or one-fourth the frequency of the VCO. The relationship between the CLKIN frequency and the output frequency is dependent on SEL. The duty cycle of the Y output signals is nominally 50%, independent of the duty cycle of the CLKIN signal.
2Y1-2Y3	22, 19, 16	O	These outputs transmit one-half the frequency of the VCO. The relationship between the CLKIN frequency and the output frequency is dependent on the frequency of the output being fed back to FBIN. The duty cycle of the Y output signals is nominally 50% independent of the duty cycle of the CLKIN signal.

ABSOLUTE MAXIMUM RATINGSover operating free-air temperature range (unless otherwise noted)⁽¹⁾

		UNIT
Supply voltage range, V_{CC}		-0.5 V to 4.6 V
Input voltage range, V_I (see ⁽²⁾)		-0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V_O (see ⁽²⁾)		-0.5 V to 5.5 V
Current into any output in the low state, I_O		64 mA
Input clamp current, $I_{IK}(V_I < 0)$		-20 mA
Output clamp current, $I_{OK}(V_O < 0)$		-50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see ⁽³⁾):	DB package	0.68 W
	DL package	0.7 W
Operating free-air temperature range, T_A		0°C to 70°C
Storage temperature range, T_{stg}		-65°C to 150°C

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- (3) The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 75 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002.

RECOMMENDED OPERATING CONDITIONS (SEE ⁽¹⁾)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	3	3.6	V
V _{IH}	High-level input voltage	2		V
V _{IL}	Low-level input voltage		0.8	V
V _I	Input voltage	0	5.5	V
I _{OH}	High-level output current		32	mA
I _{OL}	Low-level output current		32	mA
T _A	Operating free-air temperature	0	70	°C

(1) Unused inputs must be held high or low.

ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		T _A = 25°C		UNIT	
			MIN	MAX		
V _{IK}	V _{CC} = 3 V, I _I = -18 mA		1.2		V	
V _{OH}	V _{CC} = MIN to MAX ⁽¹⁾ , I _{OH} = -100 μA		V _{CC} -0.2		V	
	V _{CC} = 3 V, I _{OH} = -32 mA		2			
V _{OL}	V _{CC} = 3 V, I _{OL} = 100 μA		0.2		V	
	V _{CC} = 3 V, I _{OL} = 32 mA		0.5			
I _I	V _{CC} = 0 or MAX ⁽¹⁾ , V _I = 3.6 V		±10		μA	
	V _{CC} = 3.6 V, V _I = V _{CC} or GND		±1			
I _{OZH}	V _{CC} = 3.6 V, V _O = 3 V		10		μA	
I _{OZL}	V _{CC} = 3.6 V, V _O = 0		10		μA	
I _{CC}	V _{CC} = 3.6 V, I _O = 0, V _I = V _{CC} or GND		Outputs high		2	mA
			Outputs low		2	
			Outputs disabled		2	
C _i	V _I = V _{CC} or GND		6		pF	
C _o	V _O = V _{CC} or GND		9		pF	

(1) For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

TIMING REQUIREMENTS

over recommended ranges of supply voltage and operating free-air temperature

		MIN	MAX	UNIT
f _{clock}	Clock frequency			MHz
	When VCO is operating at four times the CLKIN frequency	25	50	
	When VCO is operating at double the CLKIN frequency	50	100	
	Input clock duty cycle	40%	60%	
Stabilization time ⁽¹⁾	After SEL		50	µs
	After $\overline{OE}$ ↓		50	
	After power up		50	
	After CLKIN		50	

(1) Time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal. In order for phase lock to be obtained, a fixed-frequency, fixed-phase reference signal must be present at CLKIN. Until phase lock is obtained, the specifications for propagation delay and skew parameters given in the switching characteristics table are not applicable.

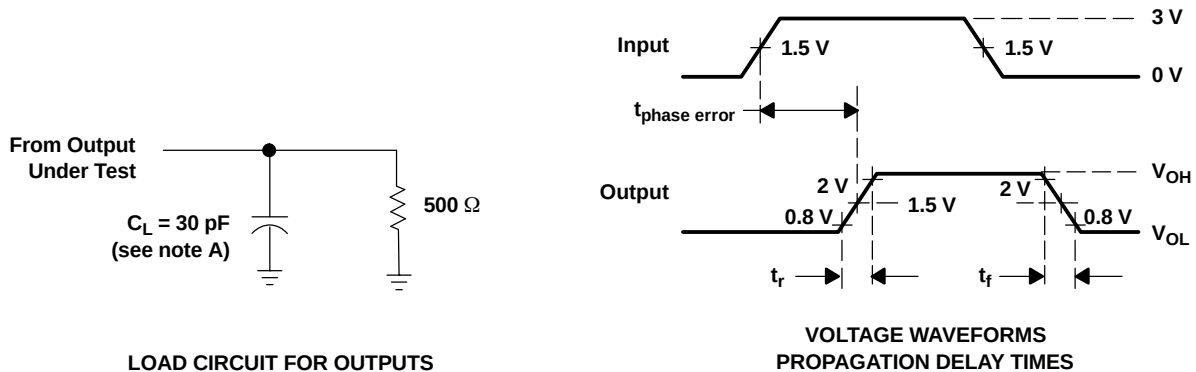
SWITCHING CHARACTERISTICS

over recommended ranges of supply voltage and operating free-air temperature, $C_L = 30$ pF (see ⁽¹⁾ and Figure 1 and Figure 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
$f_{\max}$			100		MHz
Duty cycle		Y	45%	55%	
$t_{\text{phase error}}^{(2)}$	CLKIN $\uparrow$	Y	500	+500	ps
Jitter _(pk-pk)	CLKIN $\uparrow$	Y		200	ps
$t_{\text{sk(o)}}^{(2)}$				0.5	ns
$t_{\text{sk(pr)}}$				1	ns
t_r				1.4	ns
t_f				1.4	ns

- (1) The specifications for parameters in this table are applicable only after any appropriate stabilization time has elapsed.
 (2) The propagation delay, $t_{\text{phase error}}$, is dependent on the feedback path from any output to FBIN. The $t_{\text{phase error}}$, $t_{\text{sk(o)}}$, and $t_{\text{sk(pk)}}$ specifications are only valid for equal loading of all outputs.

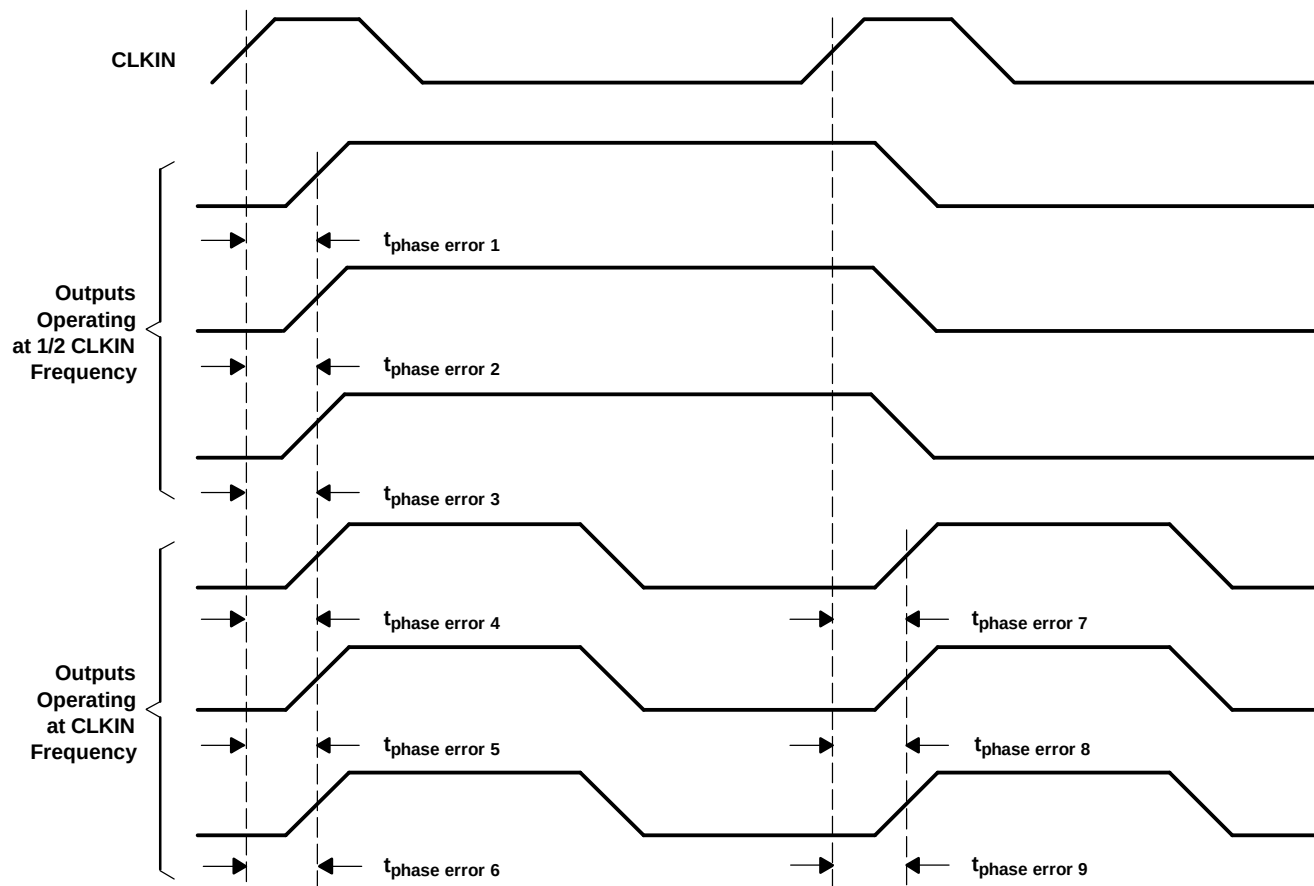
PARAMETER MEASUREMENT INFORMATION



- A. NOTES: . C_L includes probe and jig capacitance.
 B. All input pulses are supplied by generators having the following characteristics: $\text{PRR} \leq 100$ MHz, $Z_O = 50 \Omega$, $t_r \leq 2.5$ ns, $t_f \leq 2.5$ ns.
 C. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)



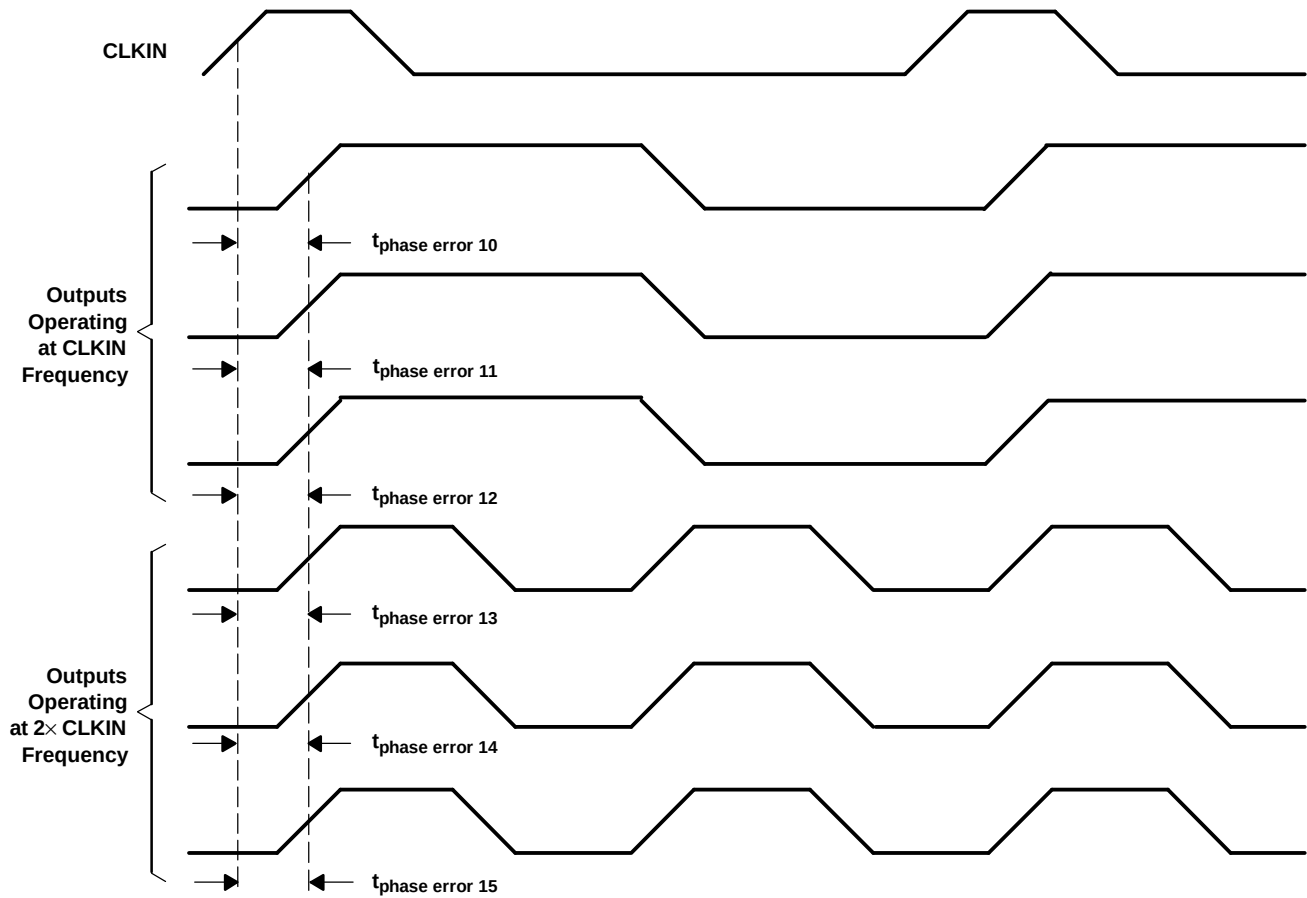
A. NOTES: . Output skew, $t_{\text{sk(o)}}$, is calculated as the greater of:

- The difference between the fastest and slowest of $t_{\text{phase error } n}$ ($n = 1, 2, \dots, 6$)
- The difference between the fastest and slowest of $t_{\text{phase error } n}$ ($n = 7, 8, 9$)

B. Process skew, $t_{\text{sk(pr)}}$, is calculated as the greater of:

- The difference between the maximum and minimum $t_{\text{phase error } n}$ ($n = 1, 2, \dots, 6$) across multiple devices under identical operating conditions.
- The difference between the maximum and minimum $t_{\text{phase error } n}$ ($n = 7, 8, 9$) across multiple devices under identical operating conditions.

Figure 2. Skew Waveforms and Calculations

PARAMETER MEASUREMENT INFORMATION (continued)

- A. NOTES: . Output skew, $t_{\text{sk(o)}}$, is calculated as the greater of:
- The difference between the fastest and slowest of $t_{\text{phase error } n}$ ($n = 10, 11, \dots, 15$)
- B. Process skew, $t_{\text{sk(pr)}}$, is calculated as the greater of:
- The difference between the maximum and minimum $t_{\text{phase error } n}$ ($n = 10, 11, \dots, 15$) across multiple devices under identical operating conditions.

Figure 3. Waveforms for Calculation of $t_{\text{sk(o)}}$ and $t_{\text{sk(pr)}}$

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
CDC536DB	Active	Production	SSOP (DB) 28	50 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC536
CDC536DB.B	Active	Production	SSOP (DB) 28	50 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC536
CDC536DBG4	Active	Production	SSOP (DB) 28	50 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC536
CDC536DBR	Active	Production	SSOP (DB) 28	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC536
CDC536DBR.B	Active	Production	SSOP (DB) 28	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC536

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

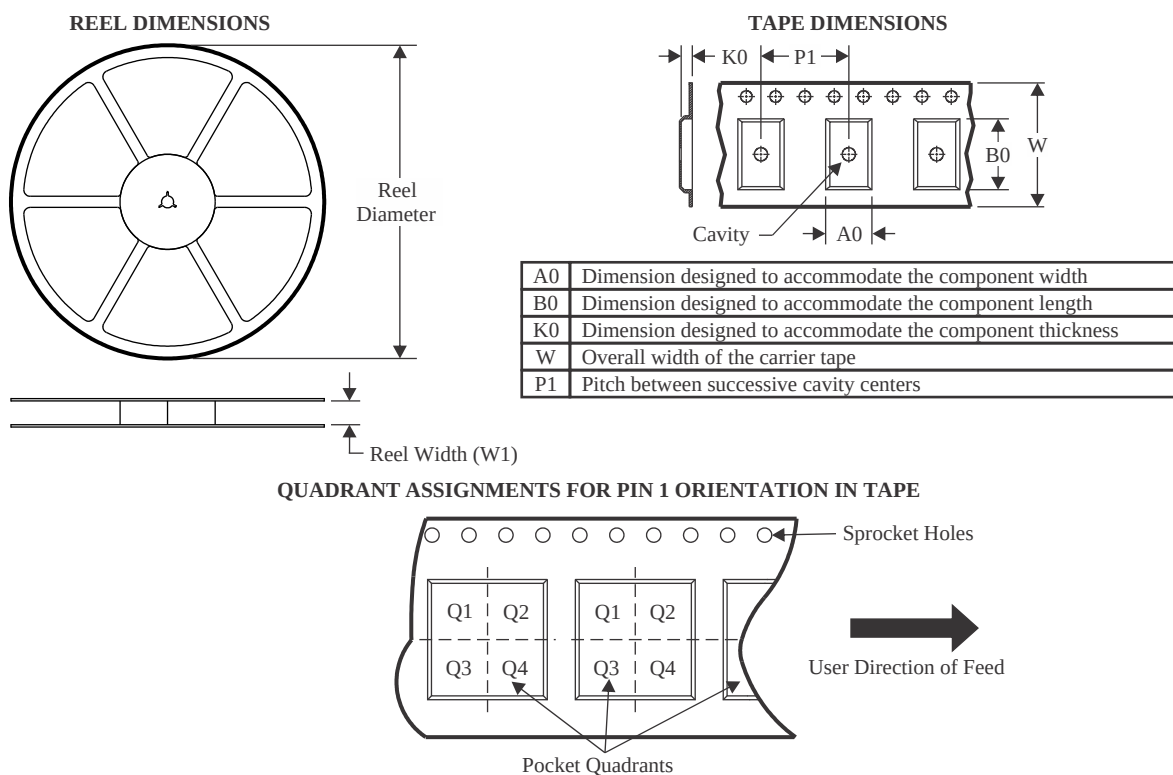
⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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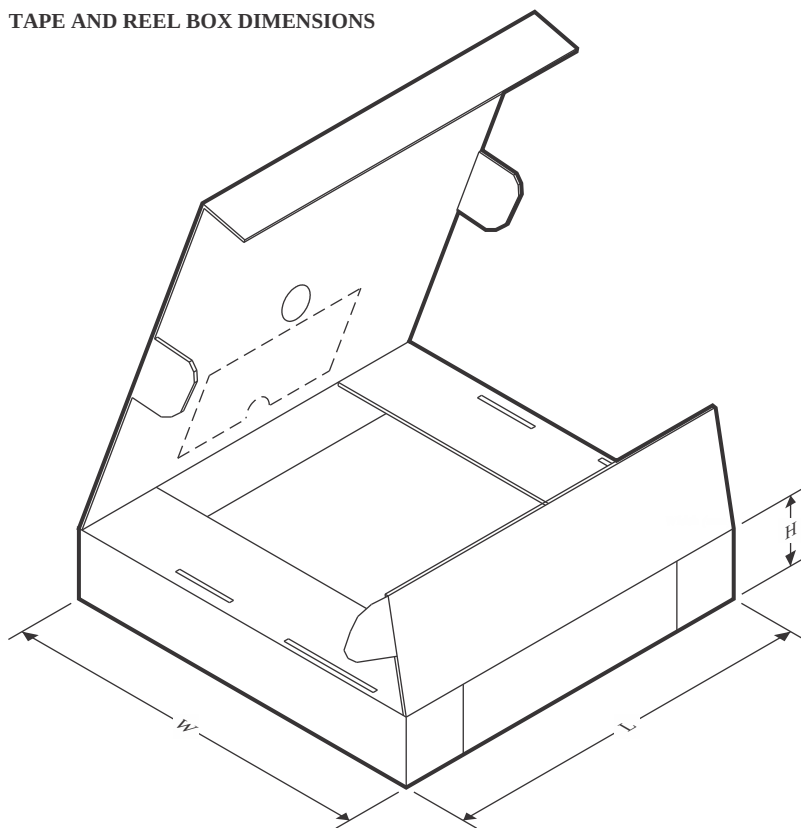
TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC536DBR	SSOP	DB	28	2000	330.0	16.4	8.1	10.4	2.5	12.0	16.0	Q1

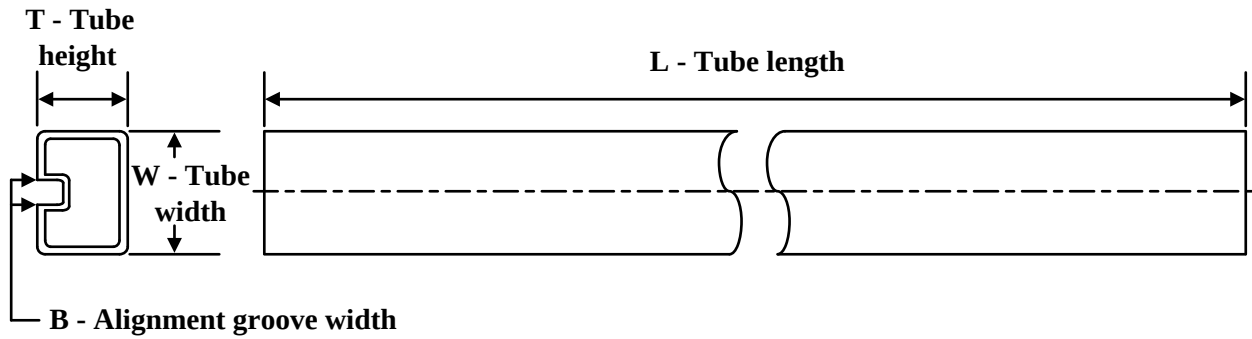
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

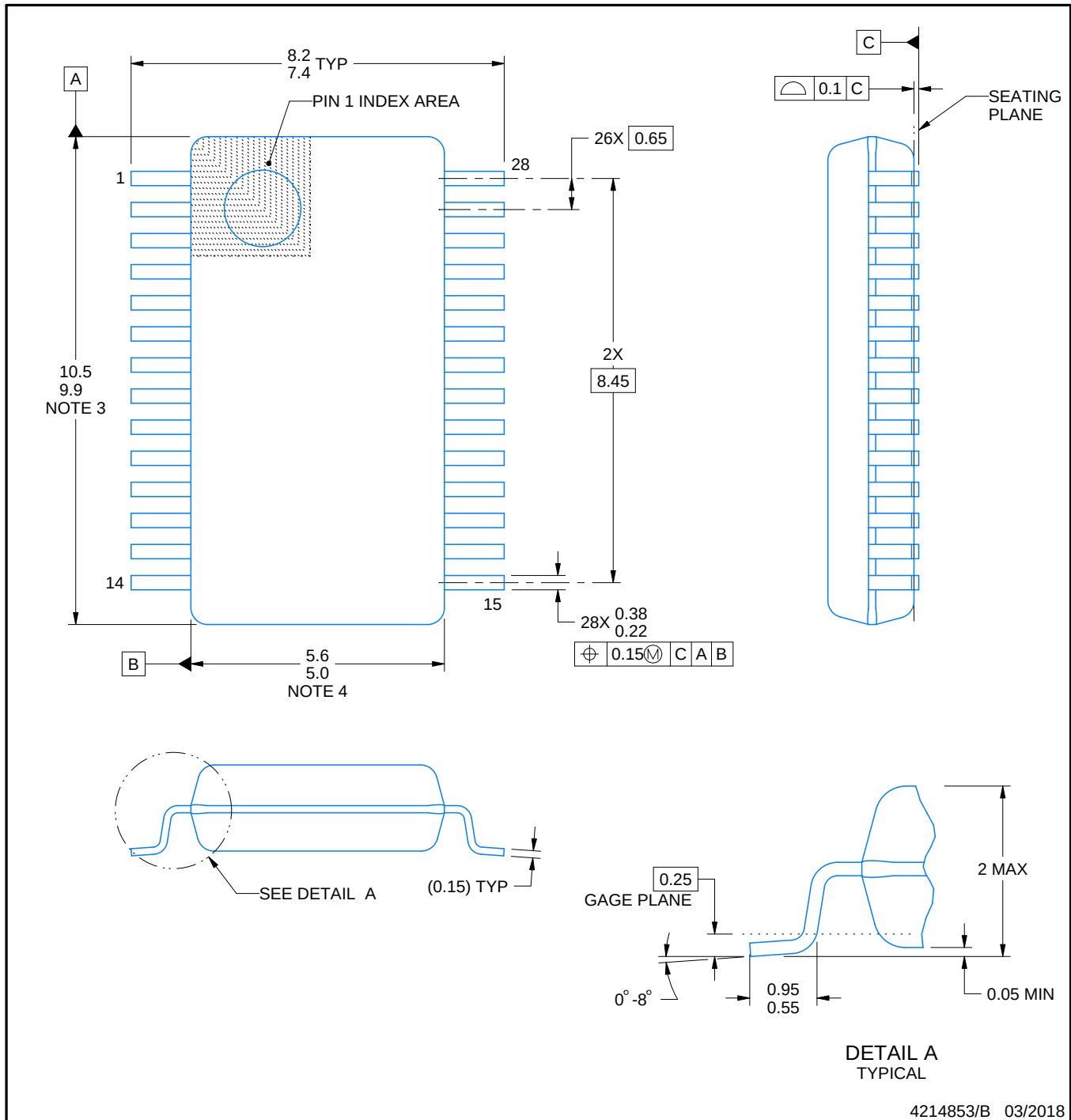
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC536DBR	SSOP	DB	28	2000	350.0	350.0	43.0

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CDC536DB	DB	SSOP	28	50	530	10.5	4000	4.1
CDC536DB.B	DB	SSOP	28	50	530	10.5	4000	4.1
CDC536DBG4	DB	SSOP	28	50	530	10.5	4000	4.1



4214853/B 03/2018

NOTES:

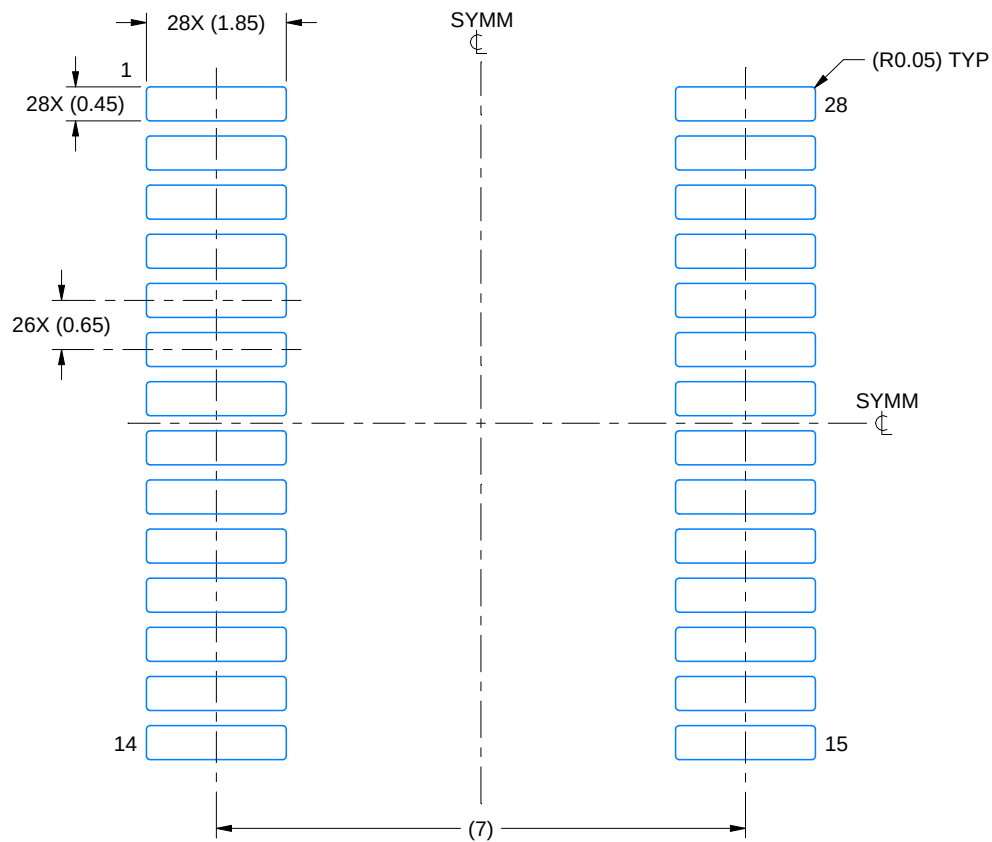
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-150.

EXAMPLE BOARD LAYOUT

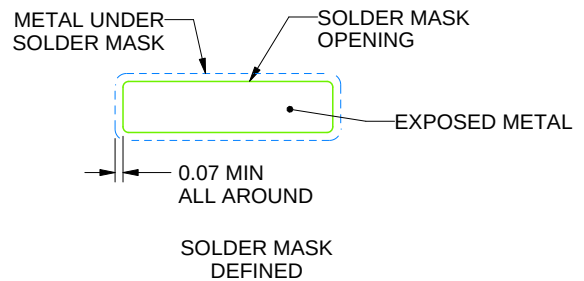
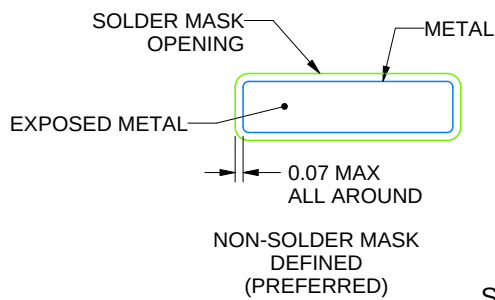
DB0028A

SSOP - 2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X



SOLDER MASK DETAILS

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NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

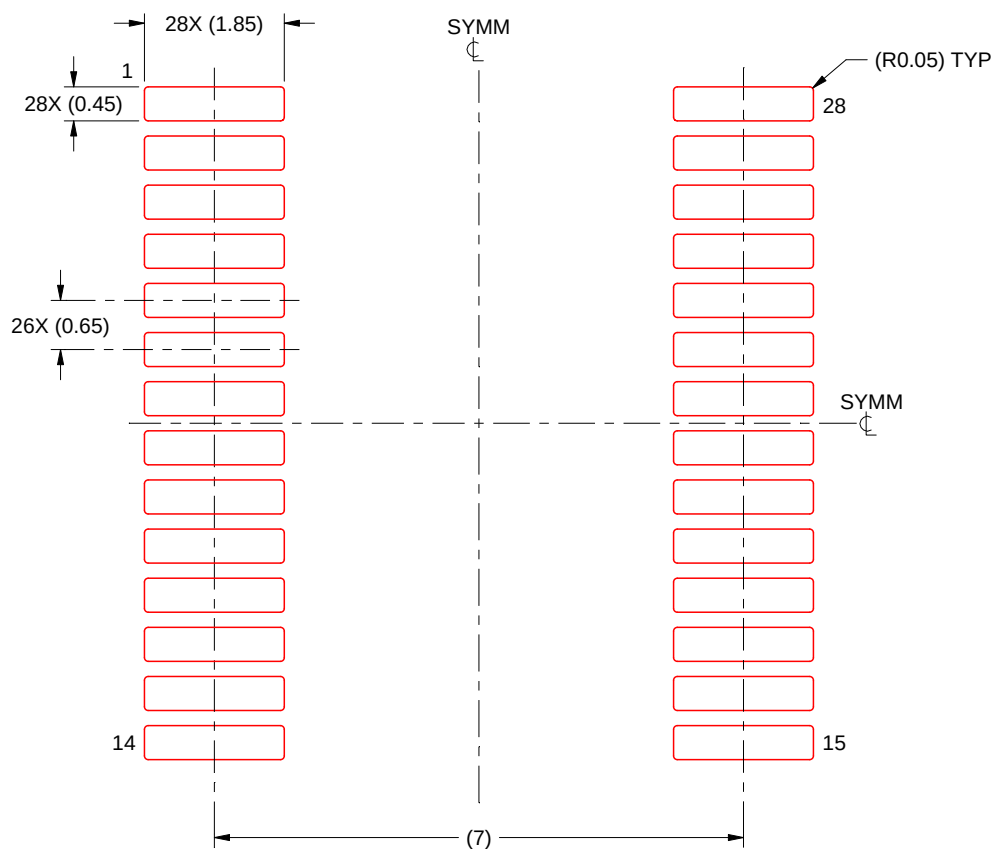
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DB0028A

SSOP - 2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4214853/B 03/2018

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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